Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/715,616	CHEN ET AL.
Examiner	Art Unit

1756

Daborah Chacko-Davis

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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updated se	erference-see arch history t out	7/20/2007	DCD		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
(430/312,311,316) updated text search only-see updated search history print out	7/20/2007	DCD		
EAST (US-PGPUB, USPAT, FPRS, EPO, JPO, DERWENT, IBM-TDB) See updated search history print out	7/20/2007	DCD		
Updated eDAN inventor search	7/20/2007	DCD		
Updated search history print out	7/23/2007	DCD		